



## Features

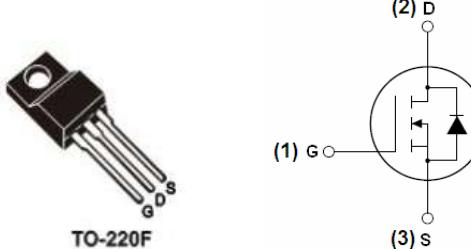
- Low Gate Charge
- Low ON Resistance
- Improved dv/dt Capability
- 100% Avalanche Tested
- RoHS compliant

## Product Summary

$V_{DS}$	650	V
$R_{DS(on),Typ}$ @ $V_{GS}=10$ V	0.65	$\Omega$
$I_D$	12	A

## Applications

- Switching Mode Power Supplies (SMPS)
- PWM Motor Controls
- AC to DC Converters
- LED Lighting
- Adapter



## ABSOLUTE MAXIMUM RATINGS ( $T_C = 25^\circ\text{C}$ , unless otherwise noted)

Parameter	Symbol	Limit	Unit
		TO-220F	
Drain to Source Voltage	$V_{DS}$	650	V
Continuous Drain Current (@ $T_C=25^\circ\text{C}$ )	$I_D$	12 <sup>(1)</sup>	A
Continuous Drain Current (@ $T_C=100^\circ\text{C}$ )		7.5 <sup>(1)</sup>	A
Drain current pulsed <sup>(2)</sup>	$I_{DM}$	48 <sup>(1)</sup>	A
Gate to Source Voltage	$V_{GS}$	$\pm 30$	V
Single pulsed Avalanche Energy <sup>(3)</sup>	$E_{AS}$	576	mJ
Peak diode Recovery dv/dt <sup>(4)</sup>	dv/dt	5	V/ns
Total power dissipation (@ $T_C=25^\circ\text{C}$ )	$P_D$	24	W
Derating Factor above 25°C		0.19	W/ $^\circ\text{C}$
Operating Junction Temperature & Storage Temperature	$T_{STG}, T_J$	-55 to + 150	$^\circ\text{C}$
Maximum lead temperature for soldering purpose	$T_L$	260	$^\circ\text{C}$

### Notes

1. Drain current is limited by maximum junction temperature.
2. Repetitive rating : pulse width limited by junction temperature.
- 3 . L = 8mH,  $I_{AS} = 12\text{A}$ ,  $V_{DD} = 50\text{V}$ ,  $R_G = 25\Omega$ , Starting at  $T_J = 25^\circ\text{C}$
4.  $I_{SD} \leq I_D$ ,  $di/dt = 100\text{A/us}$ ,  $V_{DD} \leq BV_{DSS}$ , Starting at  $T_J = 25^\circ\text{C}$

## THERMAL CHARACTERISTICS

Parameter	Symbol	Value	Unit
		TO-220F	
Thermal resistance, Junction to case (Maximum)	$R_{thjc}$	2.1	$^\circ\text{C/W}$
Thermal resistance, Junction to ambient (Maximum)	$R_{thja}$	62	$^\circ\text{C/W}$



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ASDM12N65F

650V N-Channel Power MOSFET

ELECTRICAL CHARACTERISTICS (  $T_C = 25^\circ\text{C}$  unless otherwise specified )

Parameter	Symbol	Test conditions	Min.	Typ.	Max.	Unit
<b>Off Characteristics</b>						
Drain to source breakdown voltage	$\text{BV}_{\text{DSS}}$	$V_{\text{GS}}=0\text{V}, I_D=250\mu\text{A}$	650	--	--	V
Breakdown voltage temperature coefficient	$\Delta \text{BV}_{\text{DSS}} / \Delta T_J$	$I_D=250\mu\text{A}$ , referenced to $25^\circ\text{C}$	--	0.65	--	$^\circ\text{C}$
Drain to source leakage current	$I_{\text{DSS}}$	$V_{\text{DS}}=650\text{V}, V_{\text{GS}}=0\text{V}$	--	--	1	$\mu\text{A}$
		$V_{\text{DS}}=520\text{V}, T_C=125^\circ\text{C}$	--	--	50	$\mu\text{A}$
Gate to source leakage current, forward	$I_{\text{GSS}}$	$V_{\text{GS}}=30\text{V}, V_{\text{DS}}=0\text{V}$	--	--	100	nA
Gate to source leakage current, reverse		$V_{\text{GS}}=-30\text{V}, V_{\text{DS}}=0\text{V}$	--	--	-100	nA
<b>On Characteristics</b>						
Gate threshold voltage	$V_{\text{GS(TH)}}$	$V_{\text{DS}}=V_{\text{GS}}, I_D=250\mu\text{A}$	2.5	3.5	4.5	V
Drain to source on state resistance	$R_{\text{DS(ON)}}$	$V_{\text{GS}}=10\text{V}, I_D=6\text{A}$	--	0.65	0.8	$\Omega$
Forward Transconductance	$G_{\text{fs}}$	$V_{\text{DS}}=30\text{V}, I_D=6\text{A}$	--	9.6	--	S
<b>Dynamic Characteristics</b>						
Input capacitance	$C_{\text{iss}}$	$V_{\text{GS}}=0\text{V}, V_{\text{DS}}=25\text{V}, f=1\text{MHz}$	--	1890	--	pF
Output capacitance	$C_{\text{oss}}$		--	144	--	
Reverse transfer capacitance	$C_{\text{rss}}$		--	9.9	--	
Turn on delay time	$t_{\text{d(on)}}$	$V_{\text{DS}}=325\text{V}, I_D=12\text{A}, R_G=25\Omega, V_{\text{GS}}=10\text{V}$	--	33	--	ns
Rising time	$t_{\text{r}}$		--	41	--	
Turn off delay time	$t_{\text{d(off)}}$		--	102	--	
Fall time	$t_{\text{f}}$		--	37	--	
Total gate charge	$Q_g$	$V_{\text{DS}}=520\text{V}, V_{\text{GS}}=10\text{V}, I_D=12\text{A}$	--	38	--	nC
Gate-source charge	$Q_{\text{gs}}$		--	9	--	
Gate-drain charge	$Q_{\text{gd}}$		--	13	--	
Gate Resistance	$R_g$	$V_{\text{DS}}=0\text{V}$ , Scan F mode	--	1.4	--	$\Omega$

## SOURCE TO DRAIN DIODE RATINGS CHARACTERISTICS

Parameter	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Continuous source current	$I_s$	Integral reverse p-n Junction diode in the MOSFET	--	--	12	A
Pulsed source current	$I_{\text{SM}}$		--	--	48	A
Diode forward voltage drop.	$V_{\text{SD}}$	$I_s=12\text{A}, V_{\text{GS}}=0\text{V}$	--	--	1.3	V
Reverse recovery time	$T_{\text{rr}}$	$I_s=12\text{A}, V_{\text{GS}}=0\text{V}, dI_F/dt=100\text{A}/\mu\text{s}$	--	480	--	ns
Reverse recovery Charge	$Q_{\text{rr}}$		--	4.5	--	$\mu\text{C}$
Peak Reverse Recovery Current	$I_{\text{rrm}}$	$I_s=12\text{A}, dI_F/dt=100\text{A}/\mu\text{s}$	--	18.5	--	A



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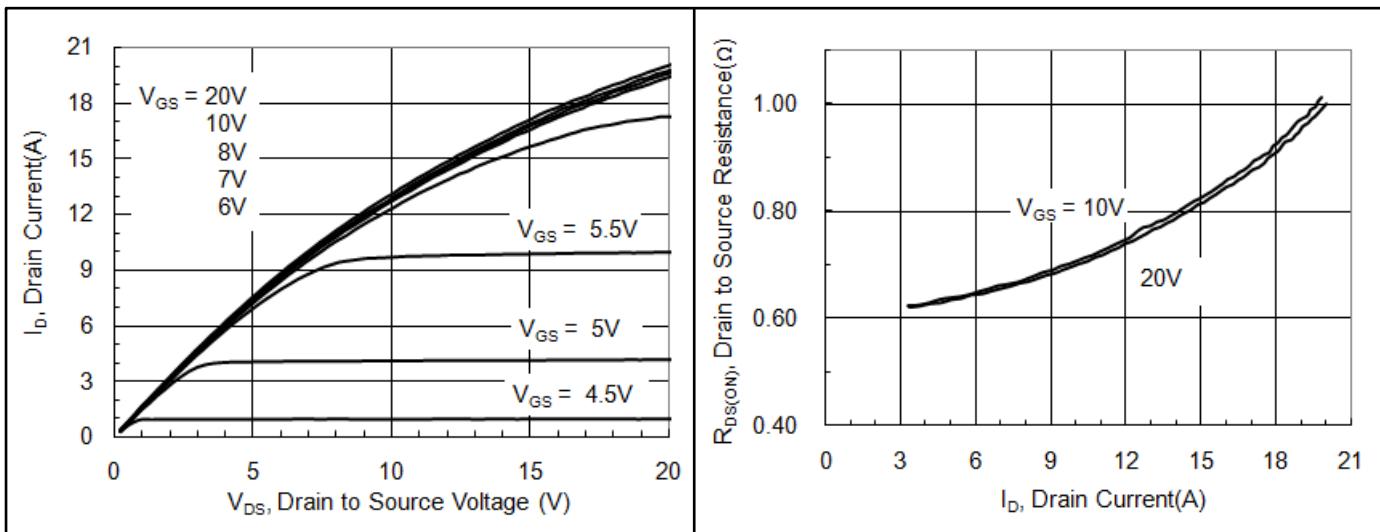


Fig1. Output characteristics

Fig2. Drain-source on-state resistance

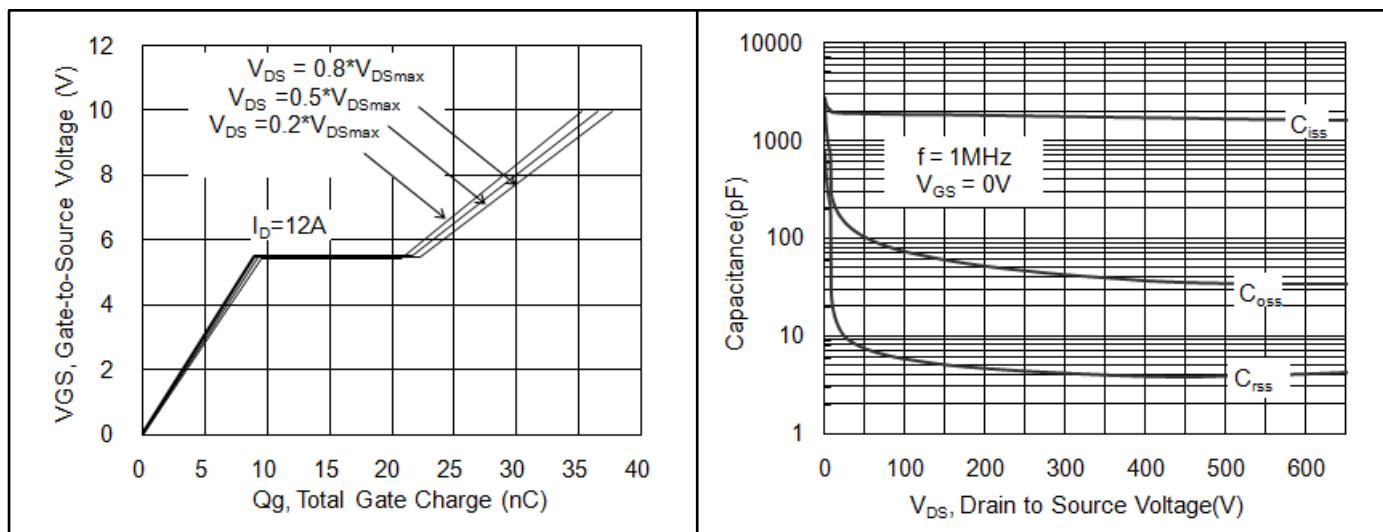
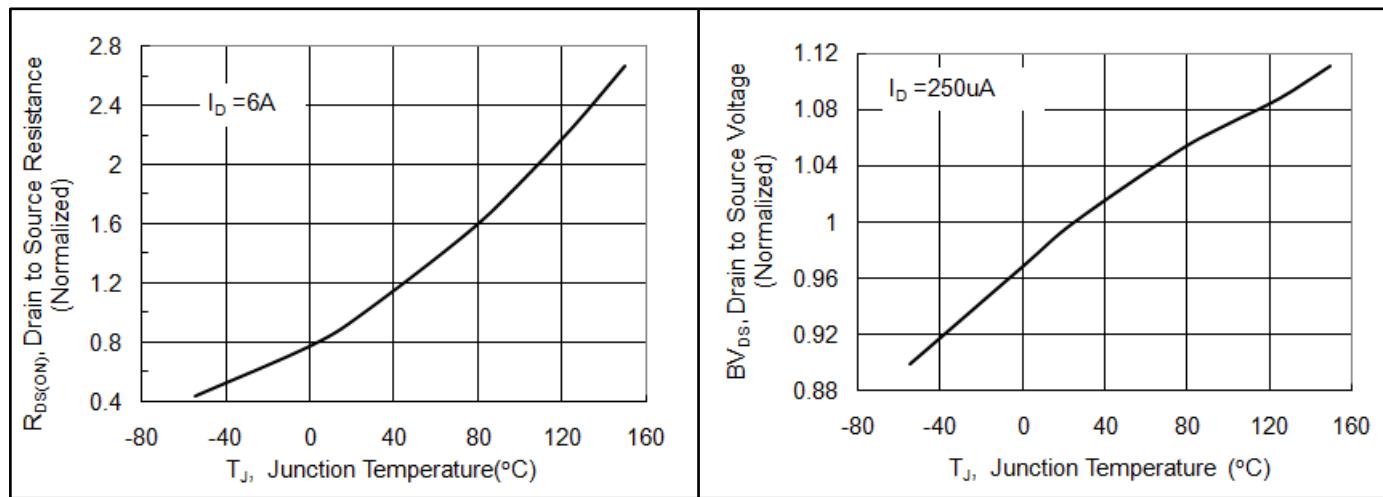


Fig3. Gate charge characteristics

Fig4. Capacitance Characteristics

Fig5.  $R_{DS(on)}$  vs junction temperatureFig6.  $BV_{DSS}$  vs junction temperature



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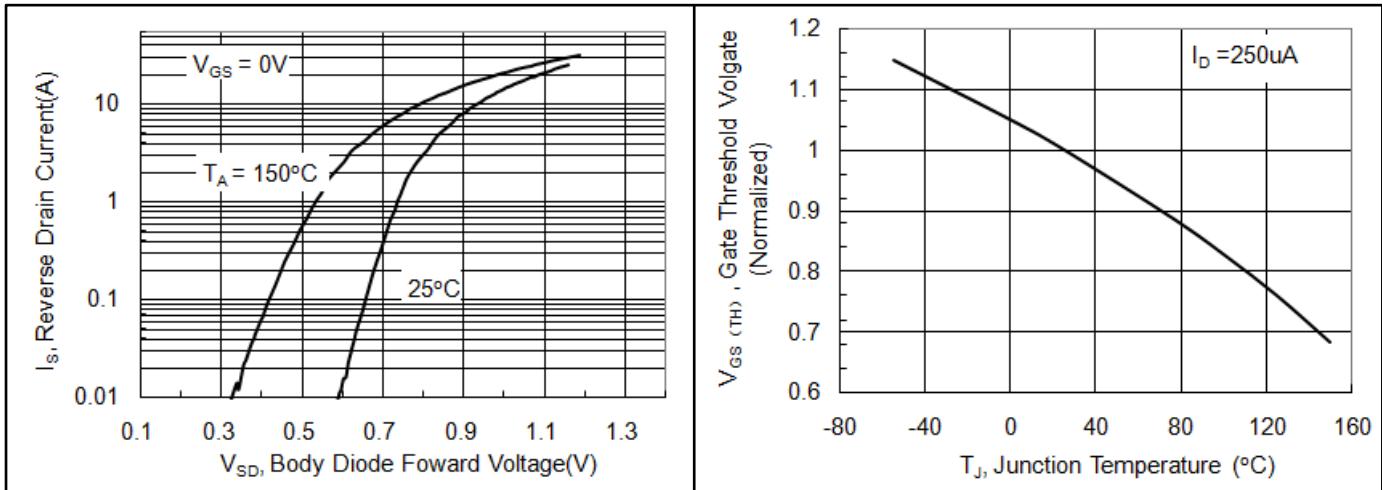


Fig 7. Forward characteristics of reverse diode

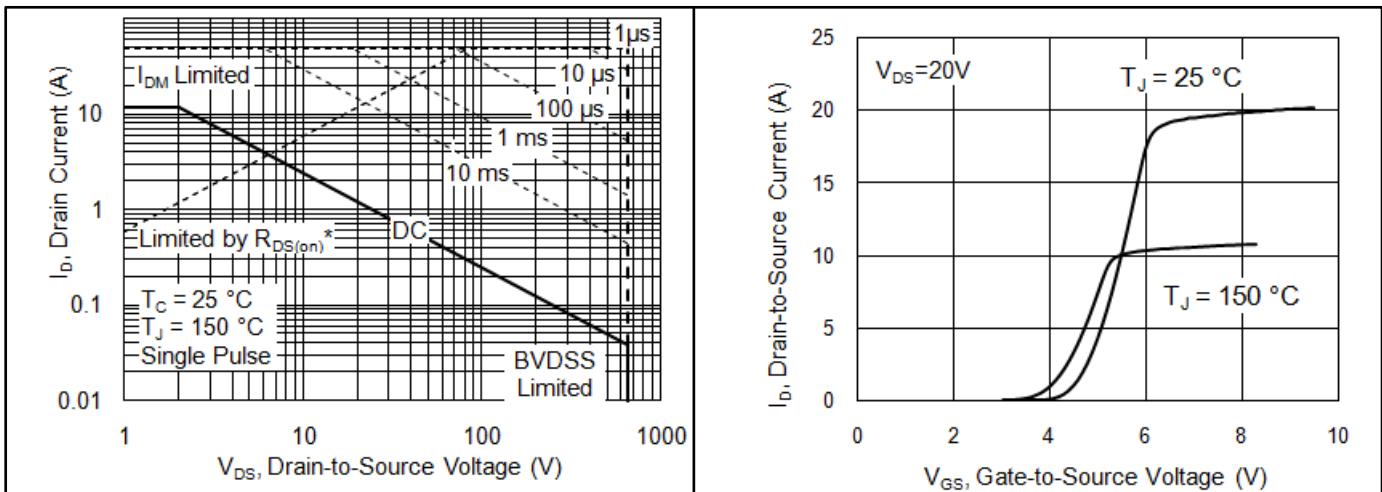
Fig 8.  $V_{GS(\text{TH})}$  vs junction temperature

Fig 9 . Safe operating area (TO-220F)

Fig 10. Transfer characteristics

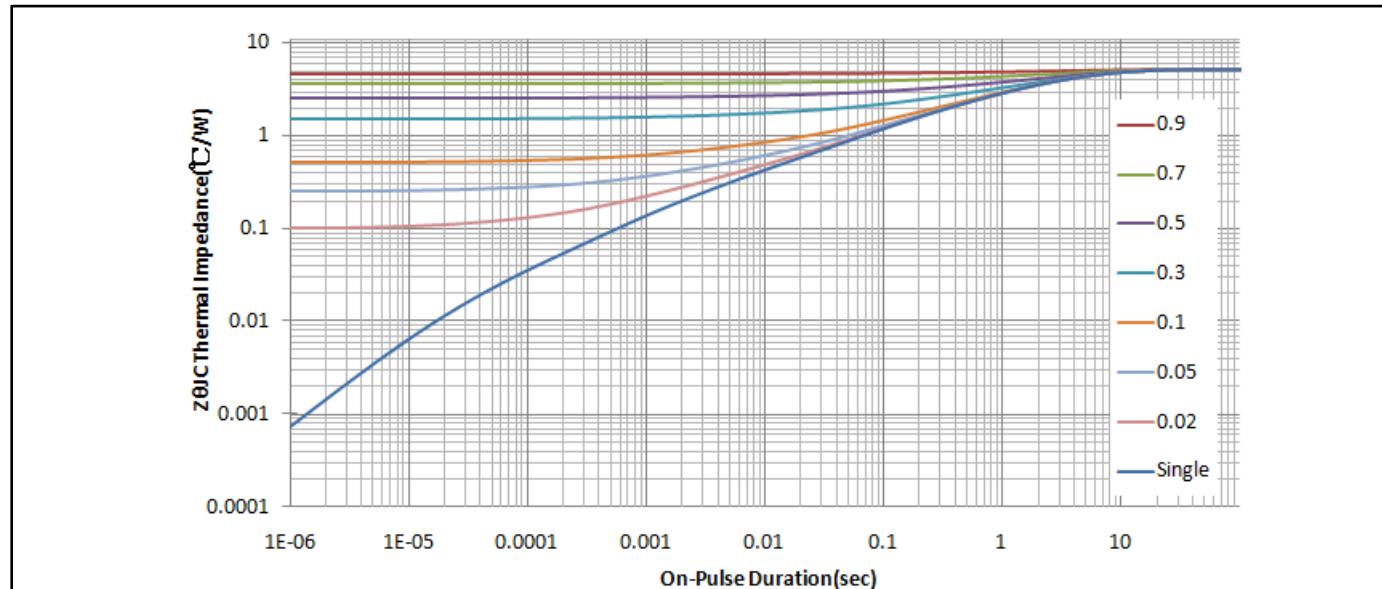


Fig 11 . Transient thermal impedance(TO-220F)



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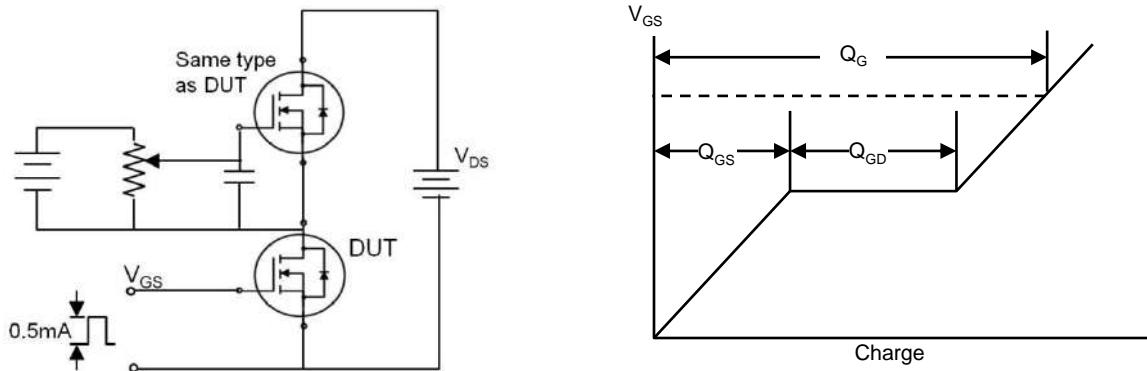


Fig 12. Gate charge test circuit &amp; waveform

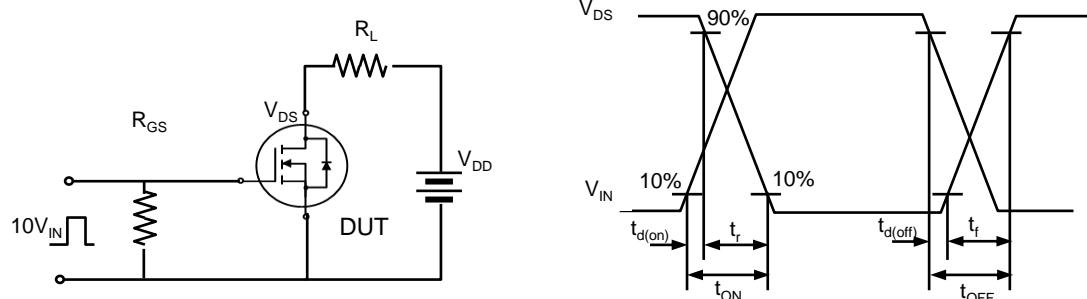


Fig 13. Switching time test circuit &amp; waveform

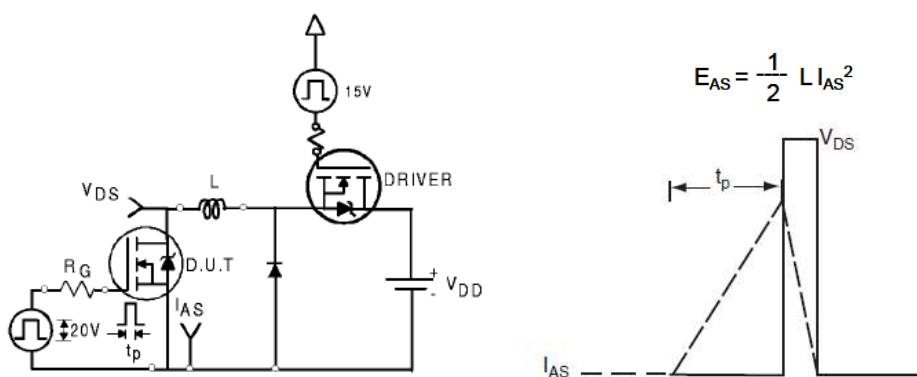


Fig 14. Unclamped Inductive switching test circuit &amp; waveform



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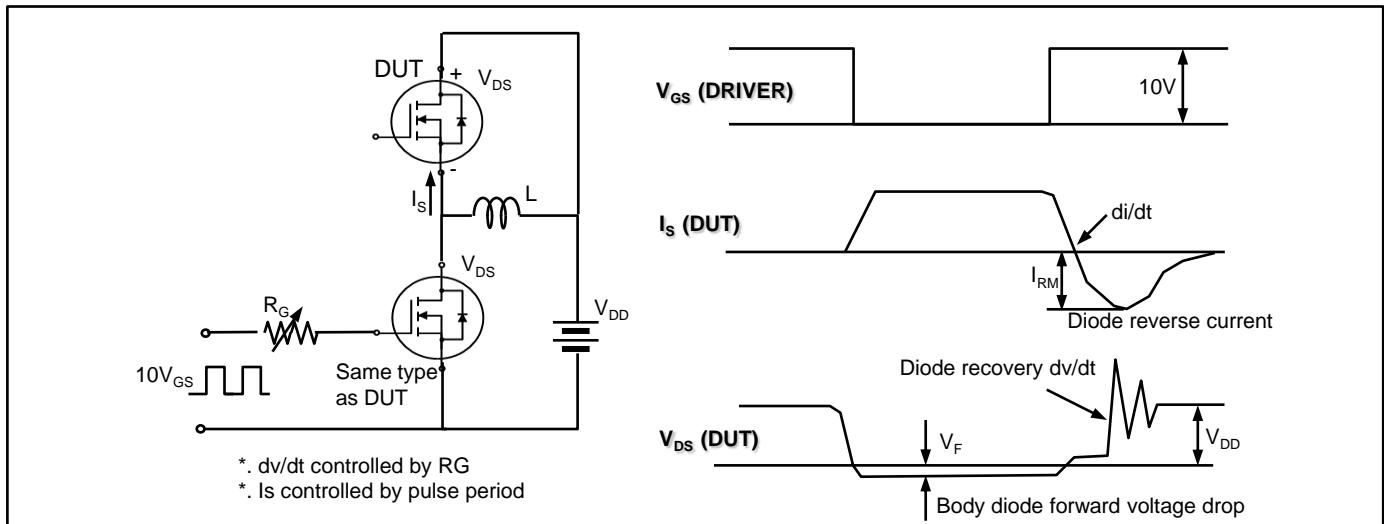
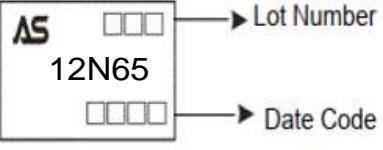


Fig 15. Peak diode recovery  $dv/dt$  test circuit & waveform

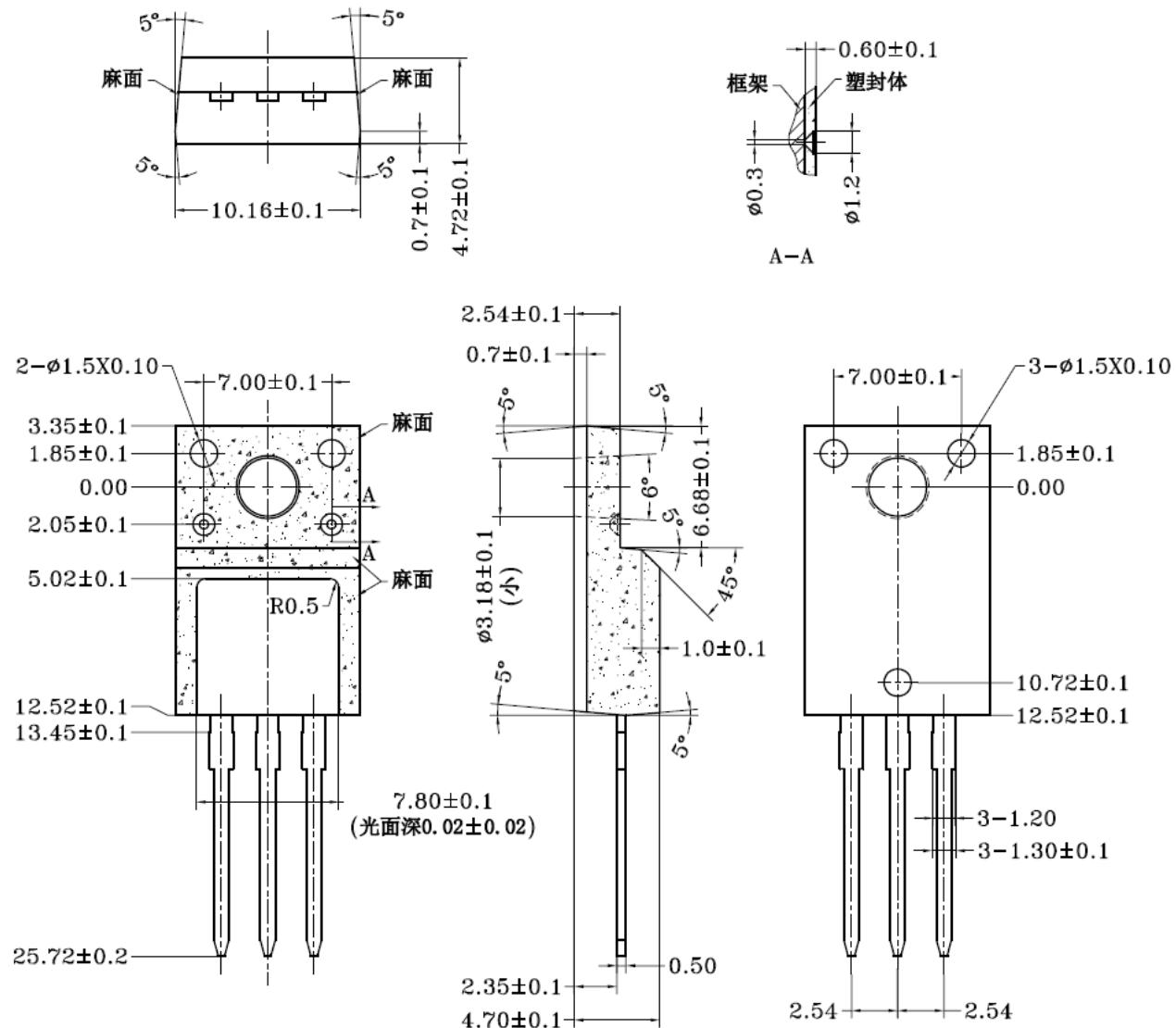
## Ordering and Marking Information

Ordering Device No.	Marking	Package	Packing	Quantity
ASDM12N65F-T	12N65	TO-220F	Tube	50/Tube

PACKAGE	MARKING
TO-220F	

## Package Dimensions

**TO-220F**





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